Please amend the Abstract of the Disclosure as follows:

An apparatus and method for absorbance detection in instrumental situations which have short absorption path lengths, such as microchip type devices, includes modulating the sample beam incident upon a sample cell to improve the sensitivity of the absorbance measurement. The modulation means includes a scanning device arranged to move the sample beam from a first position in which the sample beam is incident upon the sample area to a second position in which the sample beam is incident upon the cell.

In The Claims

1. (Amended) Apparatus for measuring absorbance comprising a light source emitting a sample beam which is incident upon a cell having a sample area, said cell being arranged to reflect said sample beam to a detector, wherein said apparatus further comprises modulation means arranged to modulate said sample beam so as to improve the sensitivity of an absorbance measurement.

2. (Amended) Apparatus as claimed in claim 1, wherein said modulation means includes a scanning device arranged to move said sample beam from a first position in which said sample beam is incident upon said sample area to a second position in which said sample beam is incident upon said cell.

3. (Amended) Apparatus as claimed in claim 2, wherein said scanning device is a linear scanning device.

4. (Amended) Apparatus as claimed in claim 3 wherein said linear scanning device is arranged to move said cell.

5. (Amended) Apparatus as claimed in claim 3, wherein said apparatus further comprises an optical element upon which said sample beam is incident and said linear scanning device is arranged to move said optical element.

6. (Amended) Apparatus as claimed in claim 4, wherein said linear scanning device is a motor.